N-channel TrenchMOS FET Rev. 01 — 3 August 2010

Objective data sheet

1. **Product profile**

1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Suitable for intermediate level gate drive sources

1.3 Applications

- 12 V and 24 V Automotive systems
- ABS/ESP
- Engine management
- HVAC

- Suitable for thermally demanding environments due to 175 °C rating
- Motors, lamps and solenoid control
- Transmission control
- Ultra high performance power switching

1.4 Quick reference data

Table 1. Quick reference data

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Symbol	Parameter	Conditions		Min	Тур	Мах	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	55	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u>	<u>[1]</u>	-	-	100	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	263	W
Static cha	racteristics						
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 5</u>		-	2.7	3.5	mΩ
Avalanche	e ruggedness						
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 100 \text{ A}; \text{V}_{\text{sup}} \leq 55 \text{ V}; \\ R_{\text{GS}} &= 50 \Omega; \text{V}_{\text{GS}} = 10 \text{V}; \\ T_{j(\text{init})} &= 25 ^\circ\text{C}; \text{ unclamped} \end{split} $		-	-	551	mJ

[1] Continuous current is limited by package.



2. Pinning information

Table 2.	Pinning	j information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	Drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S
			SOT404 (D2PAK)	

3. Ordering information

Table 3. Ordering	information		
Type number	Package		
	Name	Description	Version
BUK663R5-55C	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

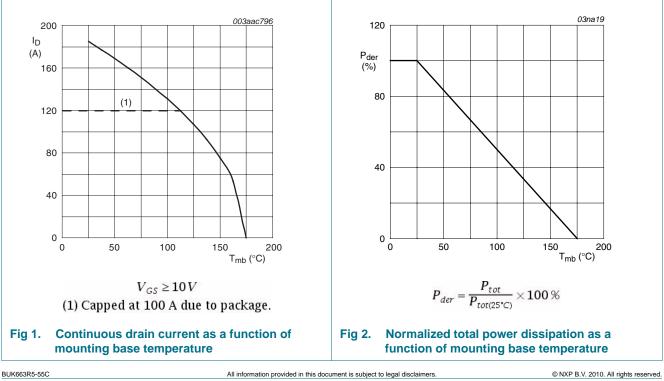
Symbol	Parameter	Conditions		Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	55	V
V _{GS}	gate-source voltage			-20	20	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	<u>[1]</u>	-	100	А
		T_{mb} = 100 °C; V_{GS} = 10 V; see Figure 1	<u>[1]</u>	-	100	А
I _{DM}	peak drain current	T_{mb} = 25 °C; $t_p \le 10 \ \mu$ s; pulsed		-	757	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	263	W
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-drain	n diode					
I _S	source current	T _{mb} = 25 °C	<u>[1]</u>	-	100	А
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	757	А
Avalanche r	uggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ I_D = 100 \text{ A}; \text{V}_{\text{sup}} \leq 55 \text{ V}; \text{R}_{\text{GS}} = 50 \Omega; \\ \text{V}_{\text{GS}} = 10 \text{ V}; \text{T}_{j(\text{init})} = 25 ^{\circ}\text{C}; \text{ unclamped} $		-	551	mJ
E _{DS(AL)R}	repetitive drain-source avalanche energy		<u>[2][3][4]</u>	-	-	J

[1] Continuous current is limited by package.

[2] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[3] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[4] Refer to application note AN10273 for further information.



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5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 3	-	-	0.57	K/W
R _{th(j-a)}	thermal resistance from junction to ambient	vertical in free air	-	60	-	K/W

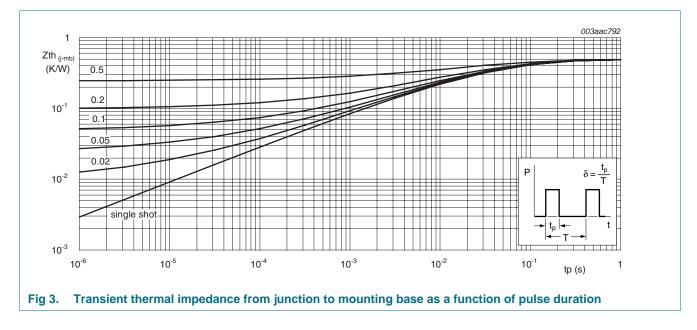


Table 5. Thermal characteristics

N-channel TrenchMOS FET

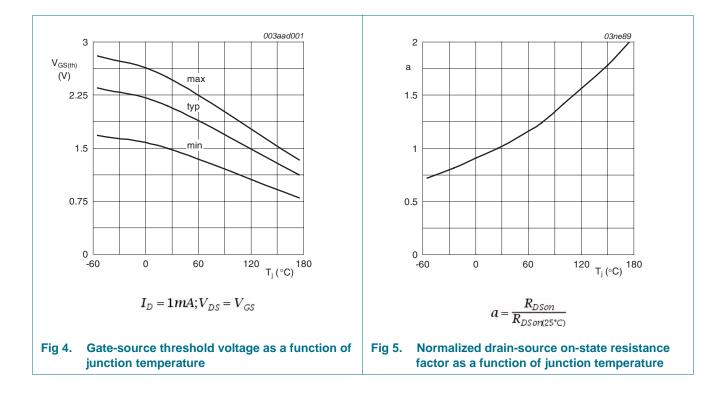
6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	cteristics					
V _{(BR)DSS}	drain-source breakdown	I _D = 250 μA; V _{GS} = 0 V; T _j = 25 °C	55	-	-	V
voltage	voltage	I _D = 250 μA; V _{GS} = 0 V; T _i = -55 °C	50	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see Figure 4	1.5	2.1	2.5	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see Figure 4	-	-	2.8	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see Figure 4	0.8	-	-	V
DSS	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μA
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.02	1	μA
GSS	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 20 \text{ V}; \text{ T}_{j} = 25 \text{ °C}$	-	2	100	nA
		$V_{DS} = 0 V; V_{GS} = -20 V; T_j = 25 °C$	-	2	100	nA
R _{DSon}	drain-source on-state resistance	V_{GS} = 5 V; I_D = 15 A; T_j = 25 °C; see <u>Figure 5</u>	-	[tbd]	[tbd]	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 5</u>	-	2.7	3.5	mΩ
		V _{GS} = 4.5 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 5</u>	-	[tbd]	[tbd]	mΩ
		V _{GS} = 10 V; I _D = 15 A; T _j = 175 °C; see <u>Figure 5</u>	-	-	7.4	mΩ
Dvnamic ch	aracteristics					
-	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$	-	[tbd]	[tbd]	nC
-		$I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$	-	[tbd] [tbd]	[tbd] [tbd]	nC nC
Q _{G(tot)}						
Q _{G(tot)} Q _{GS}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$		[tbd]	[tbd]	nC
Q _{G(tot)} Q _{GS} Q _{GD}	total gate charge gate-source charge	$I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	[tbd] [tbd]	[tbd] [tbd]	nC nC
Q _{G(tot)} Q _{GS} Q _{GD} C _{iss}	total gate charge gate-source charge gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_D = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$	-	[tbd] [tbd] [tbd]	[tbd] [tbd] [tbd]	nC nC nC
Q _{G(tot)} Q _{GS} Q _{GD} C _{iss} C _{oss}	total gate charge gate-source charge gate-drain charge input capacitance	$I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	- - -	[tbd] [tbd] [tbd] [tbd]	[tbd] [tbd] [tbd] [tbd]	nC nC nC pF
Q _{G(tot)} Q _{GS} Q _{GD} C _{iss} C _{oss} C _{rss}	total gate charge gate-source charge gate-drain charge input capacitance output capacitance	$I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	- - -	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	[tbd] [tbd] [tbd] [tbd] [tbd]	nC nC nC pF pF
Q _G (tot) Q _{GS} Q _{GD} C _{iss} C _{oss} C _{rss}	total gate charge gate-source charge gate-drain charge input capacitance output capacitance reverse transfer capacitance	$I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; \text{ f} = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$	- - -	[tbd] [tbd] [tbd] [tbd] [tbd]	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	nC nC pF pF pF
Q _{G(tot)} Q _{GS} Q _{GD} C _{iss} C _{oss} C _{rss} td(on)	total gate charge gate-source charge gate-drain charge input capacitance output capacitance reverse transfer capacitance turn-on delay time	$I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; \text{ f} = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	- - -	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	nC nC pF pF pF ns
Q _{G(tot)} Q _{GS} Q _{GD} C _{iss} C _{oss} C _{rss} t _{d(on)} t _r	total gate chargegate-source chargegate-drain chargeinput capacitanceoutput capacitancereverse transfer capacitanceturn-on delay timerise time	$I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; \text{ f} = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	- - - - - -	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	nC nC pF pF ns ns
Q _{G(tot)} Q _{GS} Q _{GD} C _{iss} C _{oss} C _{rss} d(on) r d(off) f	total gate chargegate-source chargegate-drain chargeinput capacitanceoutput capacitancereverse transfer capacitanceturn-on delay timerise timeturn-off delay time	$I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; \text{ f} = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	- - - - - -	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	nC nC pF pF ns ns ns
Q _{G(tot)} Q _{GS} Q _{GD} C _{iss} C _{oss} C _{rss} d(on) r d(off) f -D	total gate chargegate-source chargegate-drain chargeinput capacitanceoutput capacitancereverse transfer capacitanceturn-on delay timerise timeturn-off delay timefall time	$I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 30 \text{ V}; R_{L} = 1.2 \Omega; V_{GS} = 10 \text{ V};$ $R_{G(ext)} = 10 \Omega$ from drain lead 6 mm from package to centre of die ; $T_{j} = 25 \text{ °C}$ from source lead to source bond	- - - - - -	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	nC nC pF pF ns ns ns
Q _{G(tot)} Q _{GS} Q _{GD} C _{iss} C _{oss} C _{rss} C _{rss} C _{rss} C _{rss} C _{rss} C _{rss} C _{iss} C _{rss} C _{iss} C _{iss}	total gate chargegate-source chargegate-drain chargeinput capacitanceoutput capacitancereverse transfer capacitanceturn-on delay timerise timeturn-off delay timefall timeinternal drain inductanceinternal source inductance	$\begin{split} I_{D} &= 25 \text{ A}; \text{ V}_{DS} = 40 \text{ V}; \text{ V}_{GS} = 5 \text{ V} \\ I_{D} &= 25 \text{ A}; \text{ V}_{DS} = 40 \text{ V}; \text{ V}_{GS} = 10 \text{ V} \\ \\ \text{V}_{GS} &= 0 \text{ V}; \text{ V}_{DS} = 25 \text{ V}; \text{ f} = 1 \text{ MHz}; \\ \text{T}_{j} &= 25 \text{ °C} \\ \end{split}$ $\begin{aligned} \text{V}_{DS} &= 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V}; \\ \text{R}_{G(ext)} &= 10 \Omega \\ \end{aligned}$ from drain lead 6 mm from package to centre of die ; T_{j} = 25 \text{ °C} \\ \end{split}	- - - - - -	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] 4.5	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	nC nC pF pF ns ns ns ns nH
Q _{G(tot)} Q _{GS} Q _{GD} C _{iss} C _{oss} C _{rss} td(on) tr td(off) tr td(off) tr L _D L _S Source-drai	total gate chargegate-source chargegate-drain chargeinput capacitanceoutput capacitancereverse transfer capacitanceturn-on delay timerise timeturn-off delay timefall timeinternal drain inductanceinternal source inductance	$I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 30 \text{ V}; R_{L} = 1.2 \Omega; V_{GS} = 10 \text{ V};$ $R_{G(ext)} = 10 \Omega$ from drain lead 6 mm from package to centre of die ; $T_{j} = 25 \text{ °C}$ from source lead to source bond	- - - - - -	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] 4.5	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd]	nC nC pF pF ns ns ns ns ns
Q _G (tot) Q _{GS} Q _{GD} Ciss Coss Crss td(on) tr td(off) tf L _D L _S Source-drai	total gate chargegate-source chargegate-drain chargeinput capacitanceoutput capacitanceoutput capacitanceturn-on delay timerise timeturn-off delay timefall timeinternal drain inductanceinternal source inductance	$I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 5 \text{ V}$ $I_{D} = 25 \text{ A}; V_{DS} = 40 \text{ V}; V_{GS} = 10 \text{ V}$ $V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_{j} = 25 \text{ °C}$ $V_{DS} = 30 \text{ V}; R_{L} = 1.2 \Omega; V_{GS} = 10 \text{ V};$ $R_{G(ext)} = 10 \Omega$ from drain lead 6 mm from package to centre of die ; $T_{j} = 25 \text{ °C}$ from source lead to source bond pad ; $T_{j} = 25 \text{ °C}$	- - - - - -	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] 4.5 7.5	[tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] [tbd] -	nC nC pF pF ns ns ns ns nH

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BUK663R5-55C

N-channel TrenchMOS FET



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7. Package outline

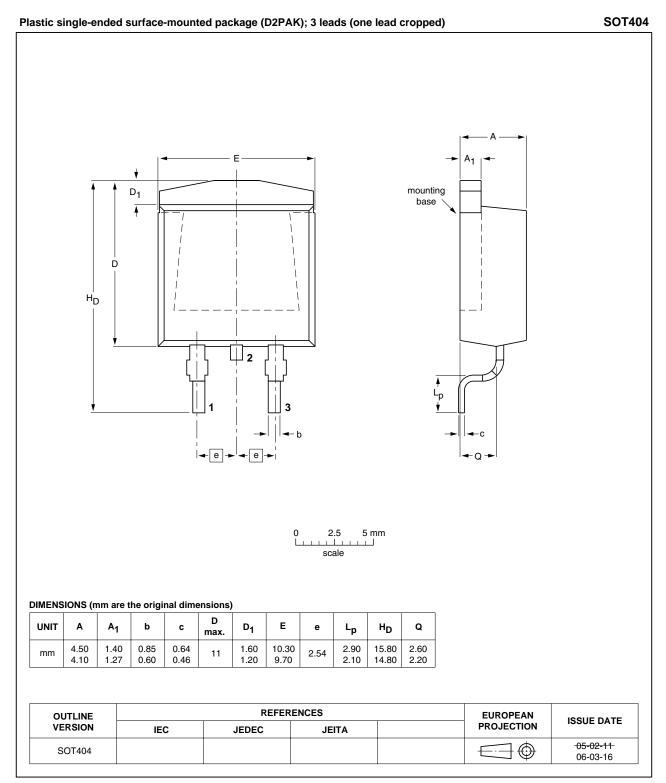


Fig 6. Package outline SOT404 (D2PAK)

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N-channel TrenchMOS FET

8. Revision history

Table 7.Revision	ble 7. Revision history				
Document ID	Release date	Data sheet status	Change notice	Supersedes	
BUK663R5-55C v.1	20100803	Objective data sheet	-	-	

Legal information 9.

9.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions'

The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product [3] status information is available on the Internet at URL http://www.nxp.com.

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11. Contents

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